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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/991,568	11/16/2001	John Wasserbauer	45921/PAN/C715	3587

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EXAMINER

SCHILLINGER, LAURA M

ART UNIT	PAPER NUMBER
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2813

DATE MAILED: 05/22/2003

Please find below and/or attached an Office communication concerning this application or proceeding.

# Office Action Summary

Application No.

09/991,568

Applicant(s)

WASSERBAUER ET AL.

Examiner

Laura M Schillinger

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-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

## Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133).
- Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

## Status

- 1) ☒ Responsive to communication(s) filed on 16 September 2002.
- 2a) ☐ This action is **FINAL**. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

## Disposition of Claims

- 4) ☒ Claim(s) 1-29 is/are pending in the application.
- 4a) Of the above claim(s) 16-29 is/are withdrawn from consideration.
- 5) ☐ Claim(s) \_\_\_\_\_ is/are allowed.
- 6) ☒ Claim(s) 1-15 is/are rejected.
- 7) ☐ Claim(s) \_\_\_\_\_ is/are objected to.
- 8) ☐ Claim(s) \_\_\_\_\_ are subject to restriction and/or election requirement.

## Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☐ The drawing(s) filed on \_\_\_\_\_ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.
- Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
- 11) ☐ The proposed drawing correction filed on \_\_\_\_\_ is: a) ☐ approved b) ☐ disapproved by the Examiner.
- If approved, corrected drawings are required in reply to this Office action.
- 12) ☐ The oath or declaration is objected to by the Examiner.

## Priority under 35 U.S.C. §§ 119 and 120

- 13) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some \* c) ☐ None of:
1. ☐ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.
3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
- \* See the attached detailed Office action for a list of the certified copies not received.
- 14) ☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).
- a) ☐ The translation of the foreign language provisional application has been received.
- 15) ☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. §§ 120 and/or 121.

## Attachment(s)

- 1) ☒ Notice of References Cited (PTO-892) 4) ☐ Interview Summary (PTO-413) Paper No(s). \_\_\_\_\_
- 2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948) 5) ☐ Notice of Informal Patent Application (PTO-152)
- 3) ☐ Information Disclosure Statement(s) (PTO-1449) Paper No(s) \_\_\_\_\_ 6) ☐ Other: \_\_\_\_\_

## **DETAILED ACTION**

### ***Election/Restrictions***

Applicant's election of claims 1-15 in Paper No. 9 is acknowledged. Because applicant did not distinctly and specifically point out the supposed errors in the restriction requirement, the election has been treated as an election without traverse (MPEP § 818.03(a)).

Claims 16-29 are withdrawn from further consideration pursuant to 37 CFR 1.142(b) as being drawn to a nonelected claims.

### ***Claim Rejections - 35 USC § 112***

The following is a quotation of the second paragraph of 35 U.S.C. 112:

The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter which the applicant regards as his invention.

Claims 2, 9, 12 and 14 recite the limitation "said wafer" without prior recitation. There is insufficient antecedent basis for this limitation in the claim.

### ***Claim Rejections - 35 USC § 102***

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

Claims 1-4, 7, 9-15 are rejected under 35 U.S.C. 102(b) as being anticipated by Leedy ('557).

In reference to claim 1, Leedy teaches a method comprising:

Forming a conductive interconnect layer adjacent the insulator layer, wherein the conductive interconnect layer electrically coupled together at least the first electrode of at least a portion of the active devices (Col.1, lines: 15-40 see also Col.3, lines: 5-10).

In reference to claim 2, Leedy teaches further comprising coupling a wafer to a test apparatus, coupling at least one test probe to the conductive interconnect layer and simultaneously applying a predetermined power to each of the active devices in the portion of active devices (Col.17, lines: 15-45).

In reference to claim 3, Leedy teaches wherein applying a predetermined power to each of the active devices in the portion of the active devices comprises driving each of the active devices in the portion of the active devices with a substantially uniform current or voltage (Col.17, lines: 35-45).

In reference to claim 4, Leedy teaches further comprising processing the conductive interconnect layer to form one or more common contact traces, wherein the one or more common contact traces electrically couple together at least the first electrode of the portion of the active devices (Col.17, lines: 15-30).

In reference to claim 7, Leedy teaches wherein processing the conductive interconnect layer between the one or more common contact traces and the first electrode of the portion of the active devices (Col.17, lines: 15-30).

In reference to claim 9, Leedy teaches further comprising coupling a wafer to a test apparatus, coupling at least one test probe to the conductive interconnect layer and simultaneously applying a predetermined portion to each of the active devices in the portion of active devices (Col.17, lines: 15-45).

In reference to claim 10, Leedy teaches further comprising forming a fuse between one or more common contact traces and the first electrode of the portion of the active devices (Col.30, lines: 1-30).

In reference to claim 11, Leedy teaches further comprising probing the active devices and blowing fuse associated with failed active devices (Col.30, lines: 20-30).

In reference to claim 12, Leedy teaches further comprising coupling the wafer to a test apparatus, coupling at least one test probe to the conductive interconnect layer and simultaneously applying a predetermined power to each of the active devices in the portion of the active devices (Col.17, lines: 15-45).

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In reference to claim 13, Leedy teaches further comprising removing the insulator layer and the conductive interconnect layer (Col.3, lines: 15-20 and 30-40).

In reference to claim 14, Leedy teaches wherein forming the conductive interconnect layer adjacent the insulator comprises coupling the wafer to a conductive liquid within a test apparatus, wherein the conductive liquid electrically couples together at least the first electrode of at least a portion of the active devices (Col.4, lines: 55-65).

In reference to claim 15, Leedy teaches further comprising removing the insulator layer and the conductive interconnect layer (Col.3, lines: 15-20 and 30-40)..

***Claim Rejections - 35 USC § 103***

Claims 5,6 and 8 are rejected under 35 U.S.C. 103(a) as being unpatentable over Leedy ('557).

Leedy teaches the above limitations however fails to explicitly teach the limitations of :

Claim 5 forming a resistor between the one or more common contact traces and the first electrode of the portion of the active devices;

Claim 6, wherein forming a resistor comprises processing the conductive interconnect layer between the one or more common contact traces and the first electrode of the portion of the active devices.

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Claim 8, wherein forming a resistor between the one or more common contact traces and the first electrode of the portion of the active devices comprises forming a resistive bridge between the one or more common contact traces and the first electrode of the portion of active devices.


However, Leedy does teach that resistors may be interconnected in a predetermined pattern to perform desired functions (Col.1, lines: 15-20) and further teaches that an ohmic contact should be provided between the contact and probe when both are made of metal (Col.10, lines: 50-55). It would have been obvious to one of ordinary skill in the art at the time the invention was made to modify Leedy's teachings to implement a resistor as an ohmic contact between the probe and contact since Leedy teaches resistors may be interconnected to perform desired functions.

### *Conclusion*

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Laura M Schillinger whose telephone number is (703) 308-6425. The examiner can normally be reached on M-T, R-F 7:00-5:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Carl W Whitehead, Jr. can be reached on (703) 308-4940. The fax phone numbers for the organization where this application or proceeding is assigned are (703) 308-7722 for regular communications and (703) 308-7722 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.

  
CARL WHITEHEAD, JR.  
SUPERVISORY PATENT EXAMINER  
TECHNOLOGY CENTER 2800

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LMS

May 16, 2003